

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10590791	HEUER ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Quoc A Tran	2176

## SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
715	234	8/28/2008	QT
715	235-250	8/28/2008	QT
Updated	Updated	2/10/2009	QT
Updated	Updated	5/21/2009	QT
Updated	Updated	11/4/2009	QT
Updated	Updated	6/15/2010	QT

## SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
NPL Search (ACM; Google Scholar; Scirus Digital Library)	8/28/2008	QT
EAST (USPAT, USPGPUB, JPO, USOCR, FPRS, EPO, DERWENT & IBM_TDB)	8/28/2008	QT
Inventors Searched Conducted- Considered Double Patent Rejection	8/28/2008	QT
Text Search Class 715/234-250	8/28/2008	QT
Updated	2/10/2009	QT
Updated	5/21/2009	QT
Updated	11/4/2009	QT
Updated	6/15/2010	QT

## INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
715	260	6/15/2010	QT
709	219 and 227	6/15/2010	QT
726	5	6/15/2010	QT

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Examiner.Art Unit 2176